U. S. Department of Commerce
John T. Connor, Secretary
National Bureau of Standards
A. V. Astin, Director

Certificate of Analysis

Standard Reference Material 726
Intermediate Purity Selenium

The following elements were detected, and the approximate limit and technique used are given.

Element		Estimated Concentration ppm
Aluminum	(Emission Spectrographic)	<1
Arsenic	(Photometric)	<2
	(Atomic Absorption)	<1
Boron	(Emission Spectrographic)	<1
Calcium	(Emission Spectrographic)	<1
Chromium	(Emission Spectrographic)	<1
Copper	(Emission Spectrographic)	<1
	(Polarographic)	<0.5
Halogens	(As chloride, chemically)	<5
Iron	(Emission Spectrographic)	1
Lead	(Emission Spectrographic)	<1
	(Polarographic)	<0.5
Magnesium	(Emission Spectrographic)	<1
Manganese	(Emission Spectrographic)	<0.3
Molybdenum	(Emission Spectrographic)	<0.3
Nickel	(Emission Spectrographic)	<0.5
Silver	(Emission Spectrographic)	<1
Sulfur	(Chemical)	12 ±3
Tellurium	(Polarographic)	0.3 ±0.1
Thallium	(Emission Spectrographic)	<0.5
Tin	(Emission Spectrographic)	<1

The following elements were not detected, and the estimated limit of detection is given.

Element		Estimated Concentration ppm
Beryllium	(Emission Spectrographic)	<0.3
Bismuth	(Emission Spectrographic)	<0.3
Cadmium	(Emission Spectrographic)	<0.3
	(Polarographic)	<0.5
Cobalt	(Emission Spectrographic)	<0.3
Indium	(Emission Spectrographic)	<0.3
Vanadium	(Emission Spectrographic)	<0.3

Analysts: Emission spectrographic, Robert Alvarez; Polarographic, E. June Maienthal; Chemical, Rolf A. Paulson; Atomic absorption, T. C. Rains; Photometric, R. W. Burke and E. R. Deardorff.

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W. WAYNE MEINKE, Chief
Office of Standard Reference Materials